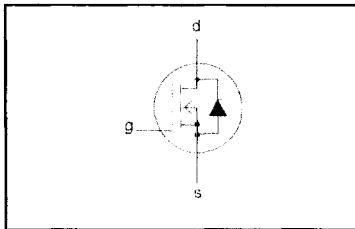


**PowerMOS transistors****FREDFET, Avalanche energy rated****PHP8ND50E, PHB8ND50E, PHW8ND50E****FEATURES**

- Repetitive Avalanche Rated
- Fast switching
- Stable off-state characteristics
- High thermal cycling performance
- Low thermal resistance
- Fast reverse recovery diode

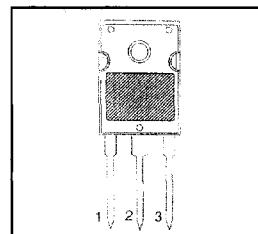
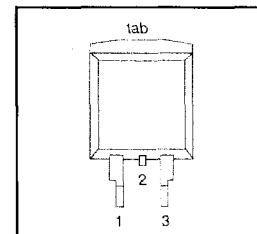
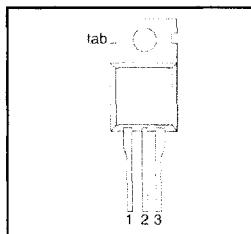
**SYMBOL****QUICK REFERENCE DATA** $V_{DSS} = 500 \text{ V}$  $I_D = 8.5 \text{ A}$  $R_{DS(ON)} \leq 0.85 \Omega$  $t_{rr} = 180 \text{ ns}$ **GENERAL DESCRIPTION**

N-channel, enhancement mode field-effect power transistor, incorporating a **Fast Recovery Epitaxial Diode (FRED)**. This gives improved switching performance in half bridge and full bridge converters making this device particularly suitable for inverters, lighting ballasts and motor control circuits.

The PHP8ND50E is supplied in the SOT78 (TO220AB) conventional leaded package.  
The PHW8ND50E is supplied in the SOT429 (TO247) conventional leaded package.  
The PHB8ND50E is supplied in the SOT404 surface mounting package.

**PINNING****SOT78 (TO220AB)****SOT404****SOT429 (TO247)**

PIN	DESCRIPTION
1	gate
2	drain <sup>1</sup>
3	source
tab	drain

**LIMITING VALUES**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DSS}$	Drain-source voltage	$T_J = 25 \text{ }^\circ\text{C to } 150 \text{ }^\circ\text{C}$	-	500	V
$V_{DGR}$	Drain-gate voltage	$T_J = 25 \text{ }^\circ\text{C to } 150 \text{ }^\circ\text{C}; R_{GS} = 20 \text{ k}\Omega$	-	500	V
$V_{GS}$	Gate-source voltage		-	$\pm 30$	V
$I_D$	Continuous drain current	$T_{mb} = 25 \text{ }^\circ\text{C}; V_{GS} = 10 \text{ V}$	-	8.5	A
$I_{DM}$	Pulsed drain current	$T_{mb} = 100 \text{ }^\circ\text{C}; V_{GS} = 10 \text{ V}$	-	5.4	A
$P_D$	Total dissipation	$T_{mb} = 25 \text{ }^\circ\text{C}$	-	34	A
$T_J, T_{stg}$	Operating junction and storage temperature range	$T_{mb} = 25 \text{ }^\circ\text{C}$	- 55	147	W
				150	$^\circ\text{C}$

<sup>1</sup> It is not possible to make connection to pin 2 of the SOT404 package.

**PowerMOS transistors**  
**FREDFET, Avalanche energy rated**

**PHP8ND50E, PHB8ND50E, PHW8ND50E**

### AVALANCHE ENERGY LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$E_{AS}$	Non-repetitive avalanche energy	Unclamped inductive load, $I_D = 8 \text{ A}$ ; $V_{DD} \leq 50 \text{ V}$ ; starting $T_j = 25^\circ\text{C}$ ; $R_{GS} = 50 \Omega$ ; $V_{GS} = 10 \text{ V}$	-	510	mJ
$E_{AR}$ $I_{AS}, I_{AR}$	Repetitive avalanche energy <sup>2</sup> Repetitive and non-repetitive avalanche current		-	13 8	mJ A

### THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{thj-mb}$	Thermal resistance junction to mounting base		-	-	0.85	K/W
$R_{thj-a}$	Thermal resistance junction to ambient	SOT78 package, in free air SOT429 package, in free air SOT404 package, pcb mounted, minimum footprint	- - -	60 45 50	- - -	K/W K/W K/W

### ELECTRICAL CHARACTERISTICS

$T_j = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}$ ; $I_D = 0.25 \text{ mA}$	500	-	-	V
$\Delta V_{(BR)DSS} / \Delta T_j$	Drain-source breakdown voltage temperature coefficient	$V_{DS} = V_{GS}$ ; $I_D = 0.25 \text{ mA}$	-	0.1	-	%/K
$R_{DS(ON)}$ $V_{GS(TO)}$ $g_{fs}$ $I_{DSS}$	Drain-source on resistance Gate threshold voltage Forward transconductance Drain-source leakage current	$V_{GS} = 10 \text{ V}$ ; $I_D = 4.8 \text{ A}$ $V_{DS} = V_{GS}$ ; $I_D = 0.25 \text{ mA}$ $V_{DS} = 30 \text{ V}$ ; $I_D = 4.8 \text{ A}$ $V_{DS} = 500 \text{ V}$ ; $V_{GS} = 0 \text{ V}$ $V_{DS} = 400 \text{ V}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 125^\circ\text{C}$ $V_{GS} = \pm 30 \text{ V}$ ; $V_{DS} = 0 \text{ V}$	2.0 3.5 - - - -	0.7 6 1 40 10	0.85 4.0 25 250 200	$\Omega$ V S $\mu\text{A}$ $\mu\text{A}$ $\text{nA}$
$I_{GSS}$	Gate-source leakage current	$I_D = 8.5 \text{ A}$ ; $V_{DD} = 400 \text{ V}$ ; $V_{GS} = 10 \text{ V}$	-	88 6 47	110 7 60	nC nC nC
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	Turn-on delay time Turn-on rise time Turn-off delay time Turn-off fall time	$V_{DD} = 250 \text{ V}$ ; $R_D = 30 \Omega$ $R_G = 9.1 \Omega$	- - - -	18 50 104 60	- - - -	ns ns ns ns
$L_d$ $L_d$ $L_s$	Internal drain inductance Internal drain inductance Internal source inductance	Measured from tab to centre of die Measured from drain lead to centre of die (SOT78 and SOT429 packages only) Measured from source lead to source bond pad	- - -	3.5 4.5 7.5	- - -	nH nH nH
$C_{iss}$ $C_{oss}$ $C_{rss}$	Input capacitance Output capacitance Feedback capacitance	$V_{GS} = 0 \text{ V}$ ; $V_{CS} = 25 \text{ V}$ ; $f = 1 \text{ MHz}$	- - -	1060 160 90	- - -	pF pF pF

<sup>2</sup> pulse width and repetition rate limited by  $T_j$  max.

**PowerMOS transistors**  
**FREDFET, Avalanche energy rated**

**PHP8ND50E, PHB8ND50E, PHW8ND50E**

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS**

$T_j = 25^\circ\text{C}$  unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$I_s$	Continuous source current (body diode)	$T_{mb} = 25^\circ\text{C}$	-	-	8.5	A
$I_{sm}$	Pulsed source current (body diode)	$T_{mb} = 25^\circ\text{C}$	-	-	34	A
$V_{SD}$	Diode forward voltage	$I_s = 8.5 \text{ A}; V_{GS} = 0 \text{ V}$	-	-	1.5	V
$t_{rr}$	Reverse recovery time	$I_s = 8.5 \text{ A}; V_{GS} = 0 \text{ V}; dI/dt = 100 \text{ A}/\mu\text{s}$ $I_s = 8.5 \text{ A}; V_{GS} = 0 \text{ V}; dI/dt = 100 \text{ A}/\mu\text{s}; 125^\circ\text{C}$	-	180	-	ns
$Q_{rr}$	Reverse recovery charge	$I_s = 8.5 \text{ A}; V_{GS} = 0 \text{ V}; dI/dt = 100 \text{ A}/\mu\text{s}$ $I_s = 8.5 \text{ A}; V_{GS} = 0 \text{ V}; dI/dt = 100 \text{ A}/\mu\text{s}; 125^\circ\text{C}$	-	0.65	-	$\mu\text{C}$
$I_{rm}$	Peak reverse recovery current	$I_s = 8.5 \text{ A}; V_{GS} = 0 \text{ V}; dI/dt = 100 \text{ A}/\mu\text{s}; 125^\circ\text{C}$	-	15	-	A

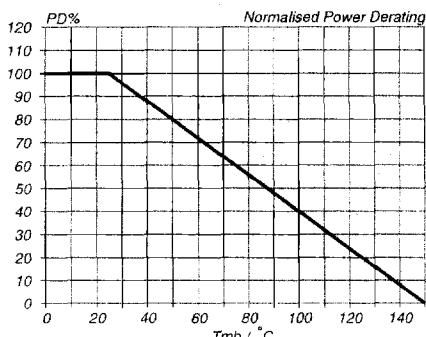


Fig. 1. Normalised power dissipation.  
 $PD\% = 100 \cdot P_D / P_{D, 25^\circ\text{C}} = f(T_{mb})$

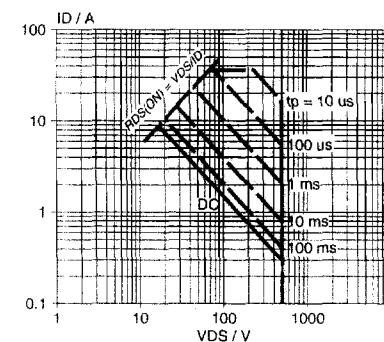


Fig. 3. Safe operating area.  $T_{mb} = 25^\circ\text{C}$   
 $I_D \& I_{DM} = f(V_{DS}); I_{DM}$  single pulse; parameter  $t_p$

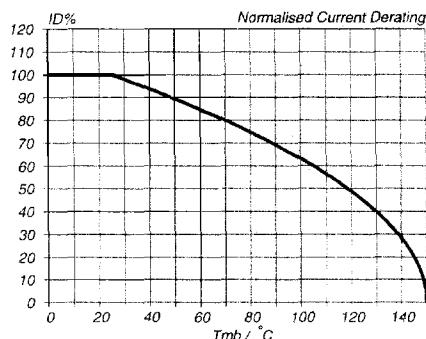


Fig. 2. Normalised continuous drain current.  
 $ID\% = 100 \cdot I_D / I_{D, 25^\circ\text{C}} = f(T_{mb})$ ; conditions:  $V_{GS} \geq 10 \text{ V}$

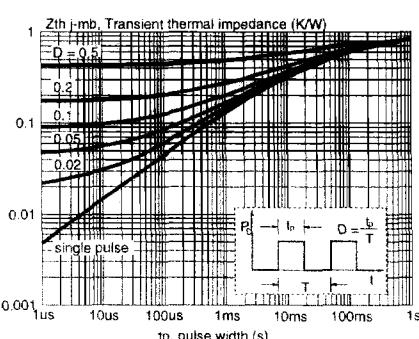


Fig. 4. Transient thermal impedance.  
 $Z_{th(j-mb)} = f(t);$  parameter  $D = t_p/T$

**PowerMOS transistors**  
**FREDFET, Avalanche energy rated**

**PHP8ND50E, PHB8ND50E, PHW8ND50E**

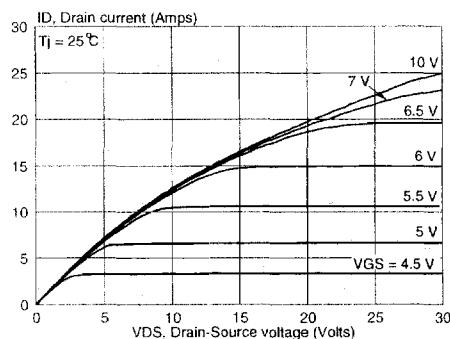


Fig.5. Typical output characteristics.  
 $I_D = f(V_{DS})$ ; parameter  $V_{GS}$

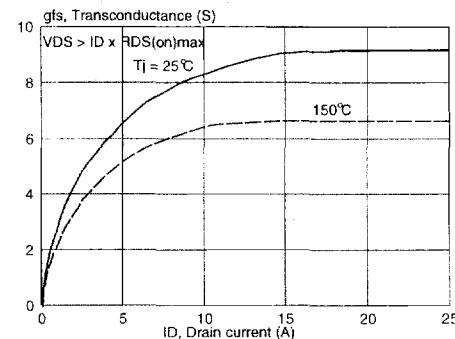


Fig.8. Typical transconductance.  
 $g_{fs} = f(I_D)$ ; parameter  $T_j$

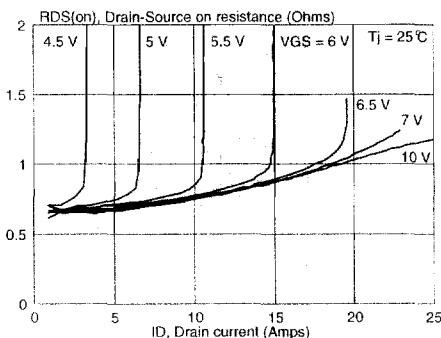


Fig.6. Typical on-state resistance.  
 $R_{DS(ON)} = f(I_D)$ ; parameter  $V_{GS}$

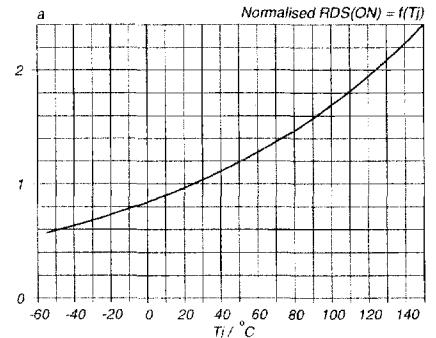


Fig.9. Normalised drain-source on-state resistance.  
 $a = R_{DS(ON)}/R_{DS(ON)25\text{ }^\circ\text{C}} = f(T_j)$ ;  $I_D = 4.25 \text{ A}$ ;  $V_{GS} = 10 \text{ V}$

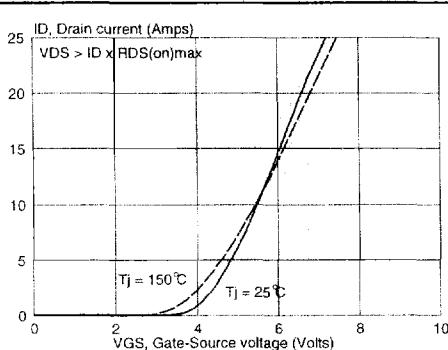


Fig.7. Typical transfer characteristics.  
 $I_D = f(V_{GS})$ ; parameter  $T_j$

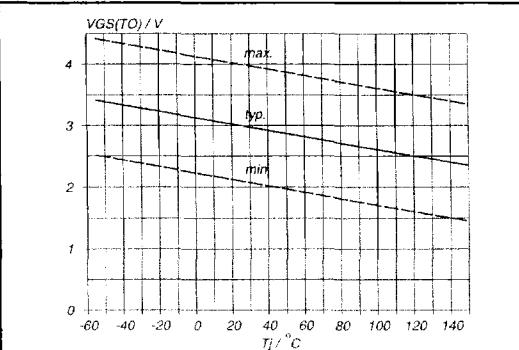


Fig.10. Gate threshold voltage.  
 $V_{GS(TO)} = f(T_j)$ ; conditions:  $I_D = 0.25 \text{ mA}$ ;  $V_{DS} = V_{GS}$

**PowerMOS transistors  
FREDFET, Avalanche energy rated**

**PHP8ND50E, PHB8ND50E, PHW8ND50E**

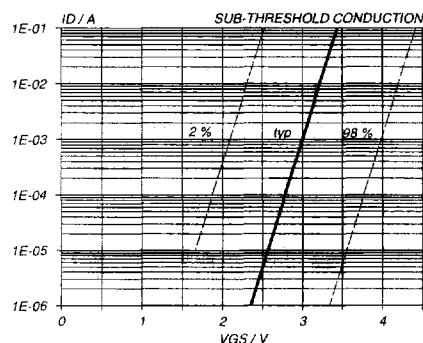


Fig. 11. Sub-threshold drain current.  
 $I_D = f(V_{GS})$ ; conditions:  $T_j = 25^\circ\text{C}$ ;  $V_{DS} = V_{GS}$

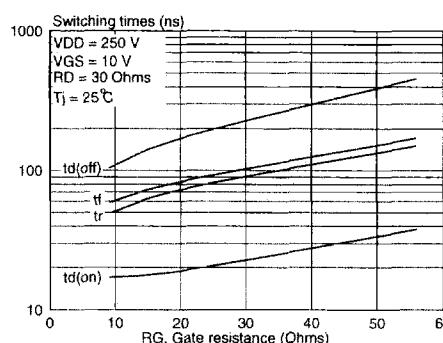


Fig. 14. Typical switching times.  
 $t_{d(on)}$ ,  $t_r$ ,  $t_{d(off)}$ ,  $t_f = f(R_G)$

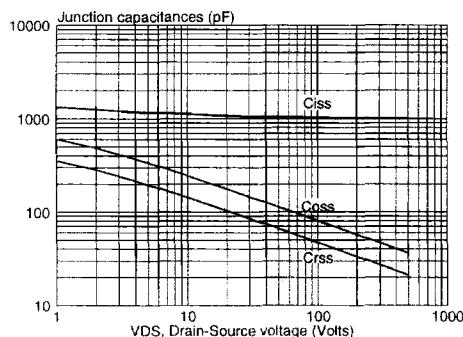


Fig. 12. Typical capacitances,  $C_{iss}$ ,  $C_{oss}$ ,  $C_{rss}$ .  
 $C = f(V_{DS})$ ; conditions:  $V_{GS} = 0\text{ V}$ ;  $f = 1\text{ MHz}$

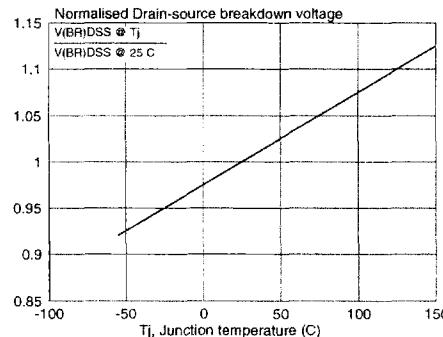


Fig. 15. Normalised drain-source breakdown voltage.  
 $V_{(BR)DSS}/V_{(BR)DSS\ 25^\circ\text{C}} = f(T_j)$

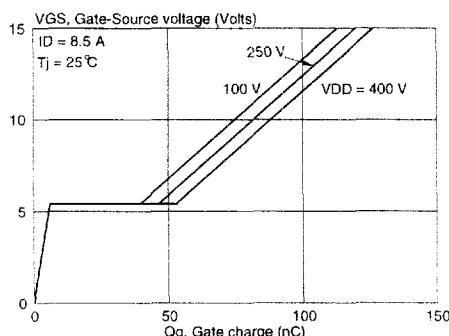


Fig. 13. Typical turn-on gate-charge characteristics.  
 $V_{GS} = f(Q_g)$ ; parameter  $V_{DS}$

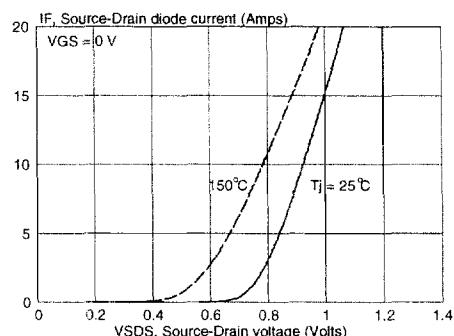


Fig. 16. Source-Drain diode characteristic.  
 $I_F = f(V_{SDS})$ ; parameter  $T_j$

**PowerMOS transistors  
FREDFET, Avalanche energy rated**

**PHP8ND50E, PHB8ND50E, PHW8ND50E**

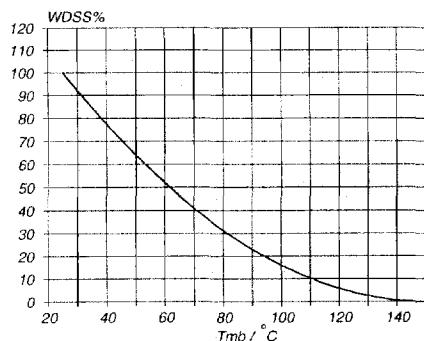


Fig. 17. Normalised non-repetitive avalanche energy rating.  
 $E_{AS}\% = f(T_{mb})$

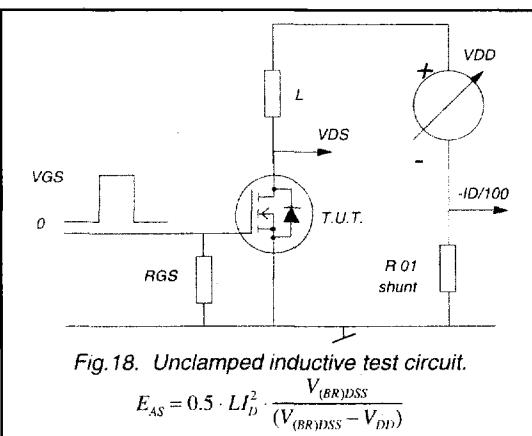


Fig. 18. Unclamped inductive test circuit.

$$E_{AS} = 0.5 \cdot L I_D^2 \cdot \frac{V_{(BR)DSS}}{(V_{(BR)DSS} - V_{PD})}$$